

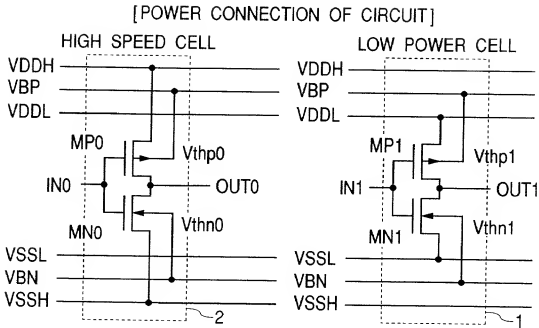
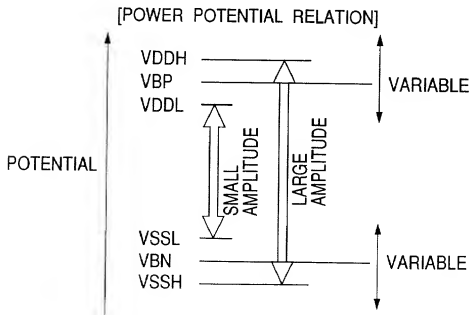
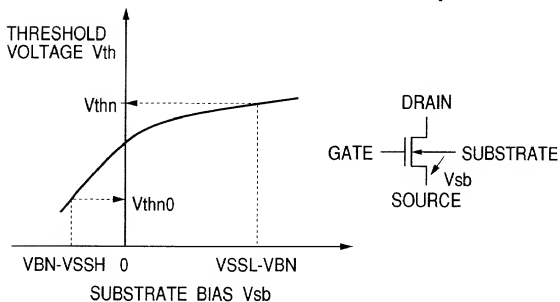
FIG. 1**FIG. 2**

FIG. 3

[INCREASE IN THRESHOLD VOLTAGE BY APPLICATION OF SUBSTRATE BIAS]

**FIG. 4**

[DECREASE IN LEAK CURRENT BY INCREASE IN THRESHOLD VOLTAGE]

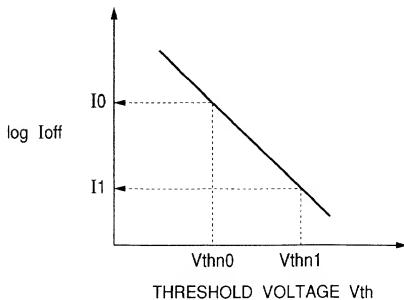


FIG. 5

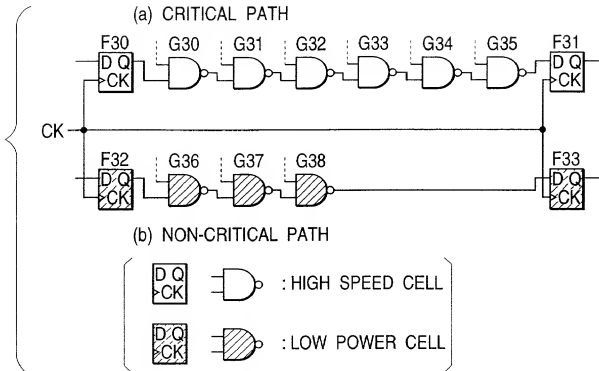


FIG. 6

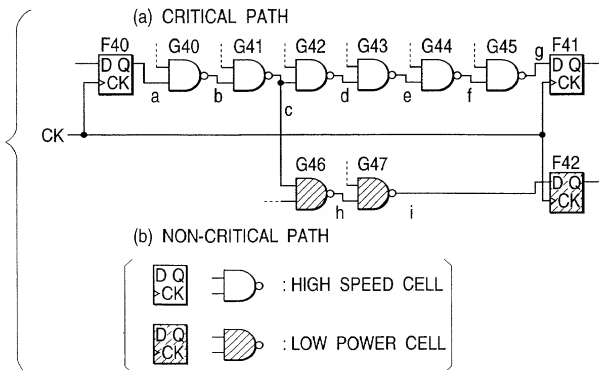


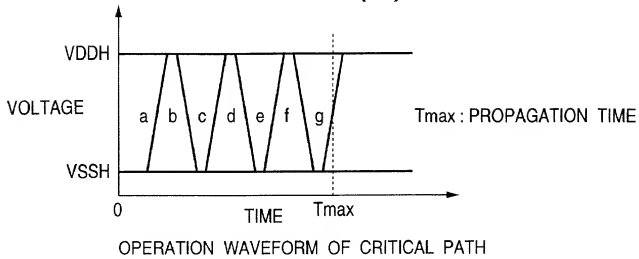
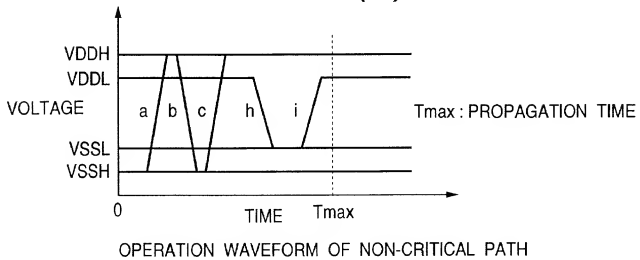
FIG. 7(A)**FIG. 7(B)**

FIG. 8

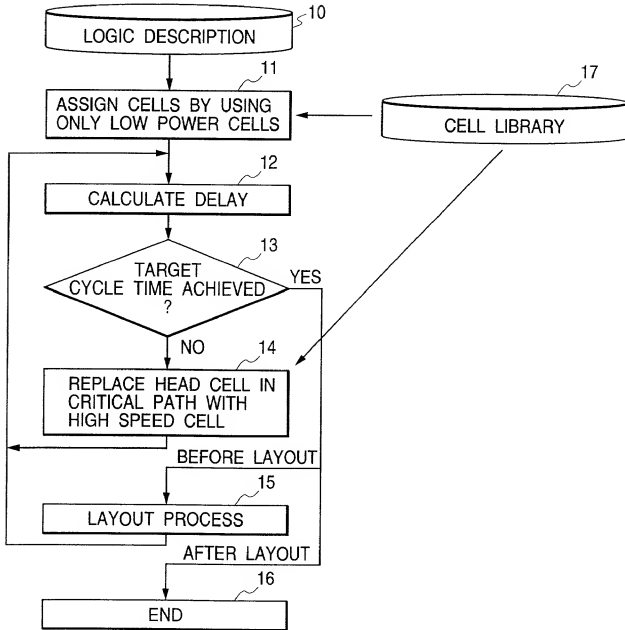


FIG. 9(A)

[CASE USING ONLY LOW POWER CELLS]

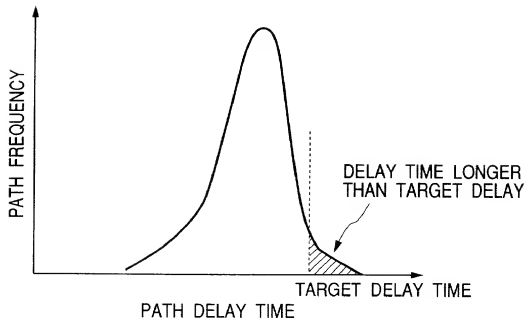


FIG. 9(B)

[CASE USING HIGH SPEED CELL FOR CRITICAL PATH]

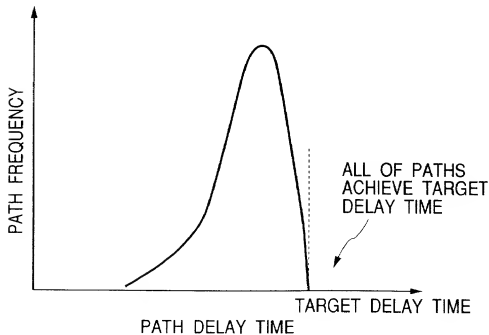


FIG. 10(A)

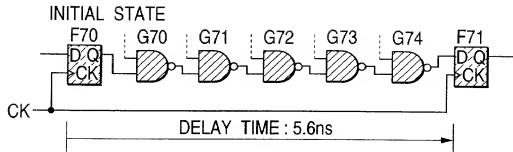


FIG. 10(B)

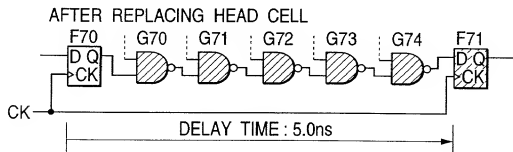


FIG. 10(C)

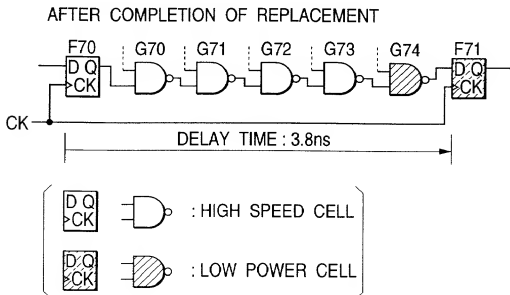


FIG. 11

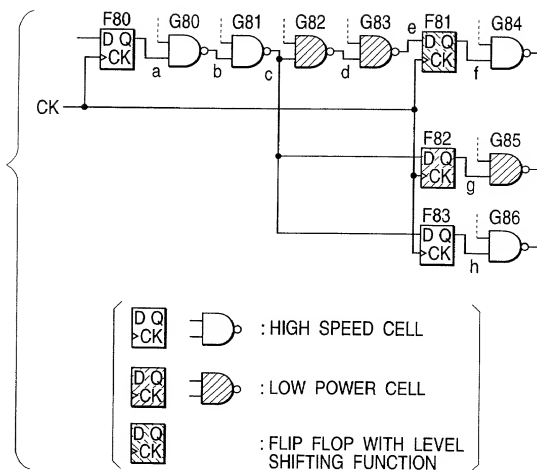


FIG. 12

[FLIP FLOP WITH LEVEL SHIFTING FUNCTION]

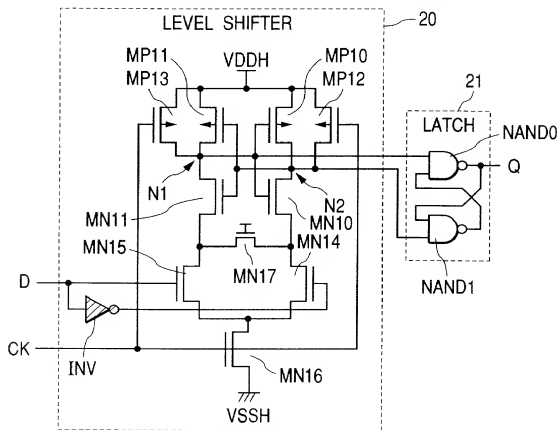
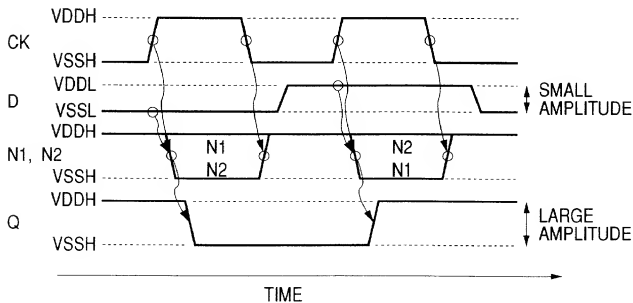
**FIG. 13**

FIG. 14

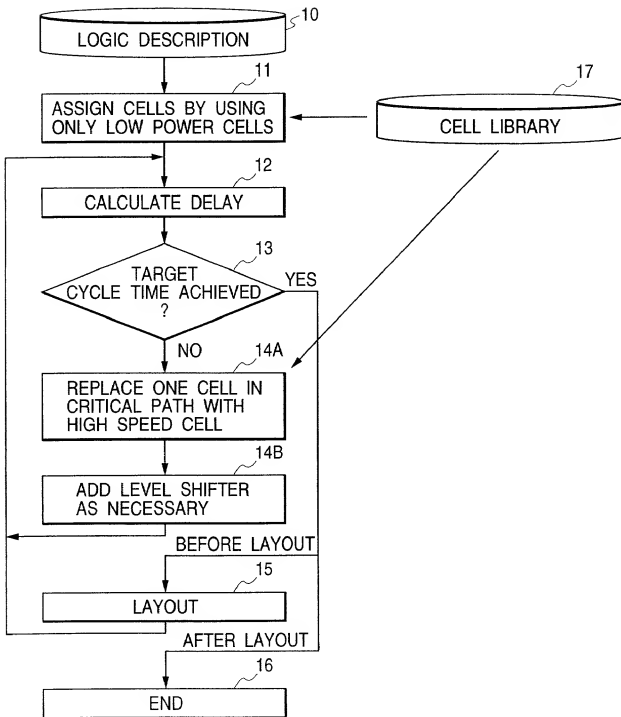


FIG. 15(A)

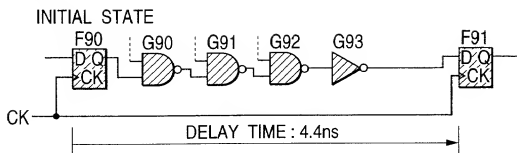


FIG. 15(B)

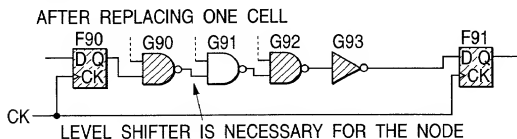


FIG. 15(C)

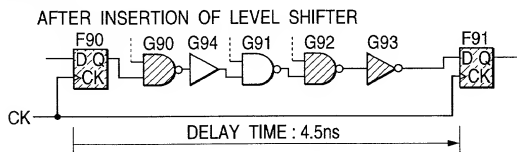


FIG. 15(D)

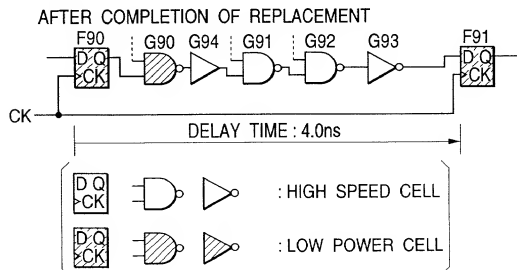


FIG. 16

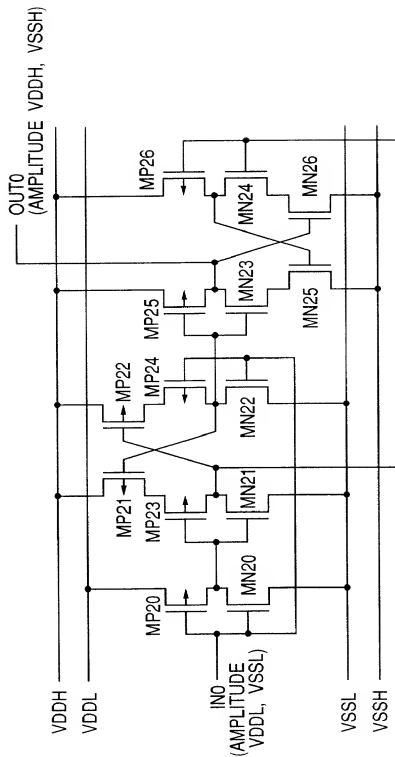


FIG. 18

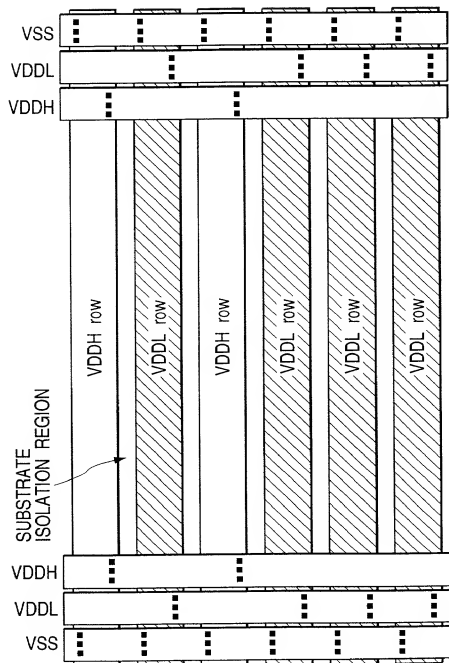


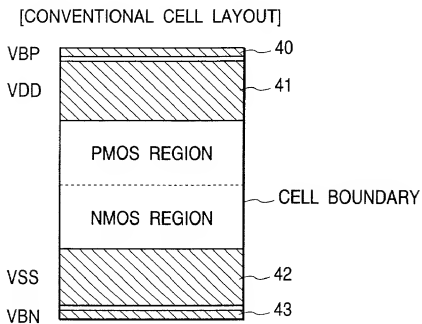
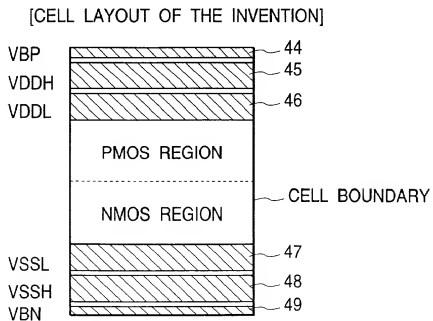
FIG. 19(A)**FIG. 19(B)**

FIG. 20(B)

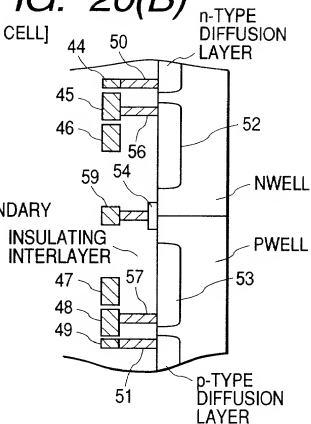


FIG. 21(B)

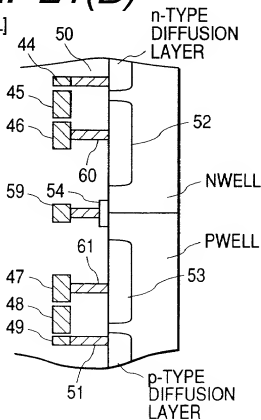


FIG. 22

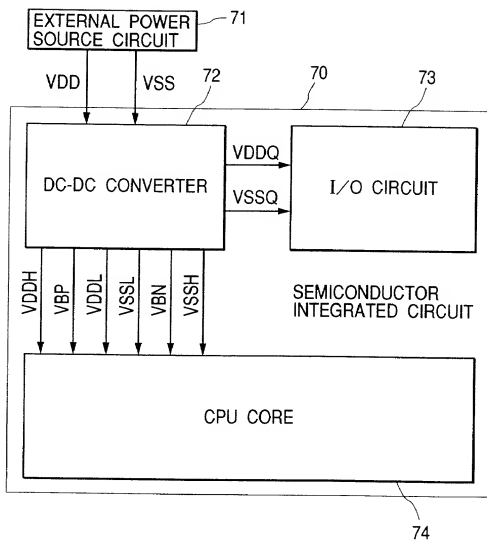


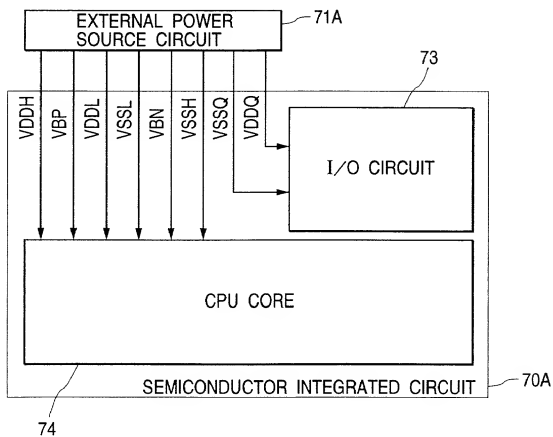
FIG. 23

FIG. 24

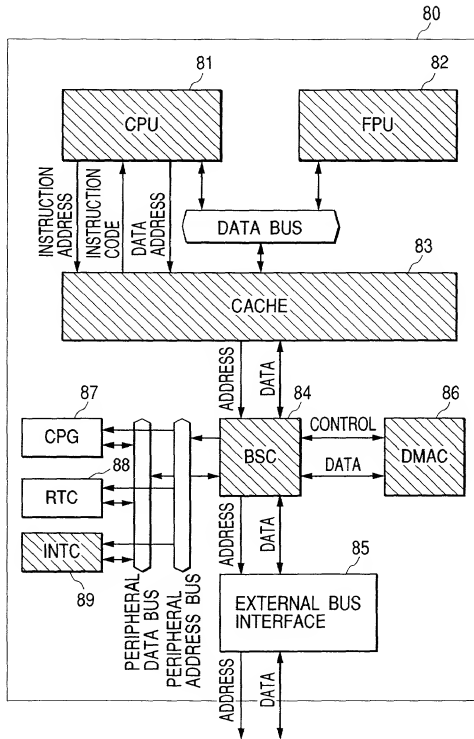


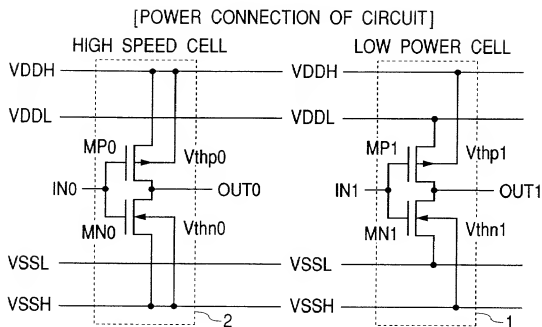
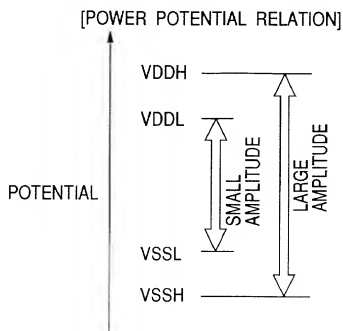
FIG. 25**FIG. 26**

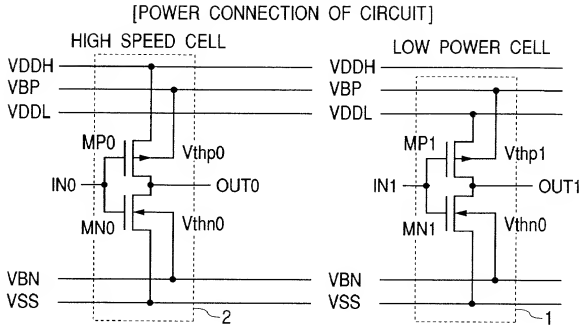
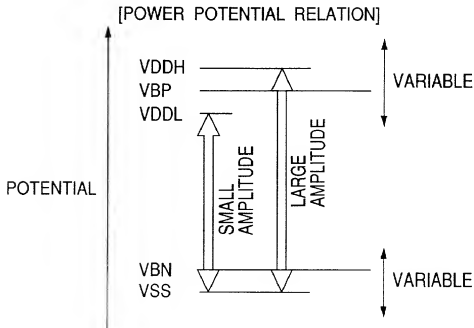
FIG. 27**FIG. 28**

FIG. 30

